Equipment Training Sheet - FEI XL 30 SEM with SE, BSE and EDAX detectors

Name:	Position:
Department:	Phone:
e-mail:	Director:
Staff Trainee	
	 Anyone needing access to MSE equipment needs to contact MSE tech staff: For initial training For subsequent usage (will receive equipment card) No secondary training of the equipment
	 Review of hazards, controls, personal protective equipment: Machine uses high voltage and high vacuum is present Gloves should be worn to minimize oils from hands contaminating chamber Any PPE and precautions should be followed for the specimens Bring the MSDS for the material to be studied if hazardous Generates X-rays Cryogenic temperatures present due to the liquid nitrogen dewar used for EDAX detector
	 Review of standard operating procedure: http://www.mse.engin.umich.edu/internal/procedures/philips-xl-sem Different imaging/collecting modes: Secondary electron (SE) Back-scattered electron (BSE) Electron dispersive analysis of X-ray's(EDAX) Samples need to be dry before beginning the pumping procedure Make certain to have the sample at appropriate height for imaging, data collection and to prevent damage to the SEM's center column 10mm For most applications, no closer than 5mm Slightly closer than 10mm position for very high magnification Further away to achieve a very low magnification image and greater depth of field Usage time starts at the beginning of the pumping procedure
	 Available supplies to help in the procedure: Tweezers, gloves, spatulas (to minimize sample contamination) Aluminum sample mounts in two sizes Copper tape and upon request carbon paste and carbon tabs
Staff Signature/	date:

Trainee Signature/date: _____